Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

10/817,090

Examiner

SAKIYAMA, RYOJI Art Unit

CXammer

Hoai-An D. Nguyen

2858

	SEAR	CHED	
Class	Subclass	Date	Examiner
324	610, 609	5/4/2005	HADN
324	602, 600	5/4/2005	HADN
324	525, 123C	5/4/2005	HADN
324	135, 139	5/4/2005	HADN
324	436, 442	5/4/2005	HADN
324	236, 239	5/4/2005	HADN
324	649, 650	5/4/2005	HADN
324	691, 713	5/4/2005	HADN
702	65, 198	5/4/2005	HADN
702	107, 117	5/4/2005	HADN
702	189-191	5/4/2005	HADN
379	30, 377	5/4/2005	HADN
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73	335.03	5/4/2005	HADN

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Class	Subclass	Date	Examiner
324	610	5/4/2005	HADN
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text search in EAST.	5/4/2005 ·	HADN
Consulted with Examiner A. Deb.	5/4/2005	HADN
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Search Notes	(continued)
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10/817,090	SAKIYAMA, RYOJI
Examiner	Art Unit
Hoai-An D. Nguyen	2858

	SEAR	CHED	
Class	Subclass	Date	Examiner
327	100	5/4/2005	HADN
600	399, 400	5/4/2005	HADN
600	442, 506	5/4/2005	HADN
600	547	5/4/2005	HADN
324	158.1	5/5/2005	HADN

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SEARCH STRATEGY)  DATE EX		
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